

2SA2210

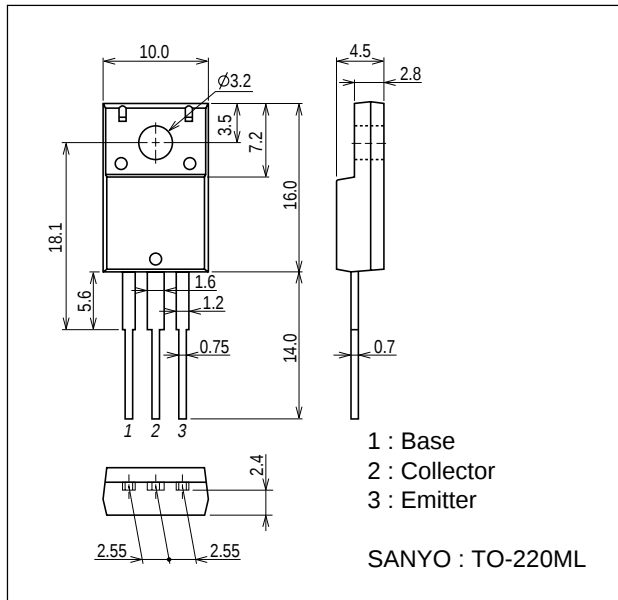
Electrical Characteristics at $T_a=25^\circ\text{C}$

Parameter	Symbol	Conditions	Ratings			Unit
			min	typ	max	
Collector Cutoff Current	I_{CBO}	$V_{CB}=-40\text{V}$, $I_E=0\text{A}$			-10	μA
Emitter Cutoff Current	I_{EBO}	$V_{EB}=-4\text{V}$, $I_C=0\text{A}$			-10	μA
DC Current Gain	h_{FE}	$V_{CE}=-2\text{V}$, $I_C=-1\text{A}$	150		450	
Gain-Bandwidth Product	f_T	$V_{CE}=-10\text{V}$, $I_C=-1\text{A}$		140		MHz
Output Capacitance	C_{ob}	$V_{CB}=-10\text{V}$, $f=1\text{MHz}$		215		pF
Collector-to-Emitter Saturation Voltage	$V_{CE(sat)}$	$I_C=-7\text{A}$, $I_B=-350\text{mA}$		-200	-500	mV
Base-to-Emitter Saturation Voltage	$V_{BE(sat)}$	$I_C=-7\text{A}$, $I_B=-350\text{mA}$			-1.2	V
Collector-to-Base Breakdown Voltage	$V_{(BR)CBO}$	$I_C=-100\mu\text{A}$, $I_E=0\text{A}$	-50			V
Collector-to-Emitter Breakdown Voltage	$V_{(BR)CEO}$	$I_C=-1\text{mA}$, $R_{BE}=\infty$	-50			V
Emitter-to-Base Breakdown Voltage	$V_{(BR)EBO}$	$I_E=-100\mu\text{A}$, $I_C=0\text{A}$	-6			V
Turn-ON Time	t_{on}	See specified Test Circuit.		60		ns
Storage Time	t_{stg}	See specified Test Circuit.		270		ns
Fall Time	t_f	See specified Test Circuit.		20		ns

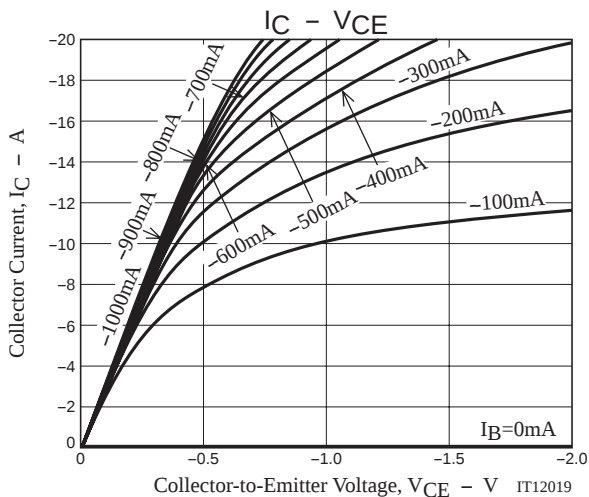
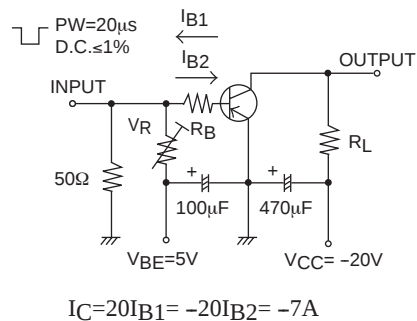
Package Dimensions

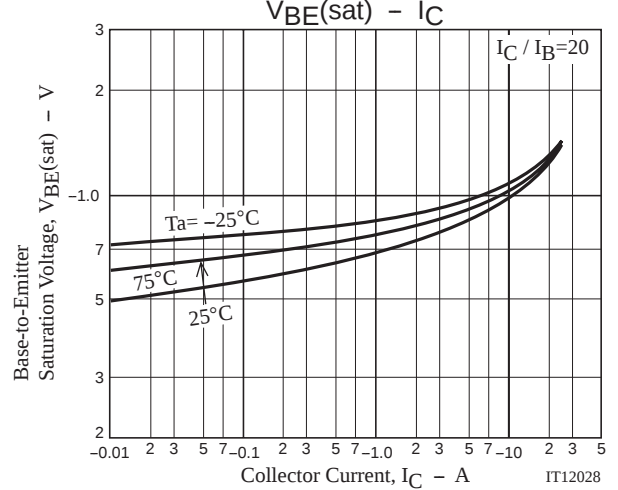
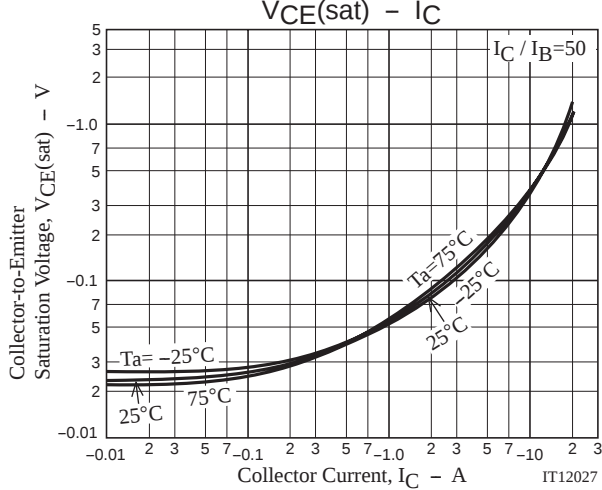
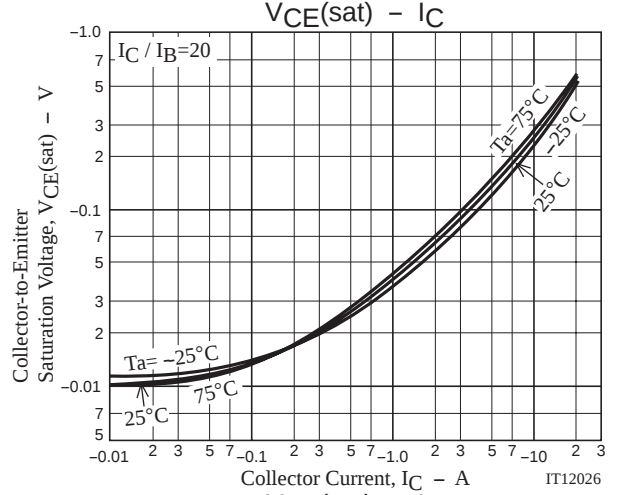
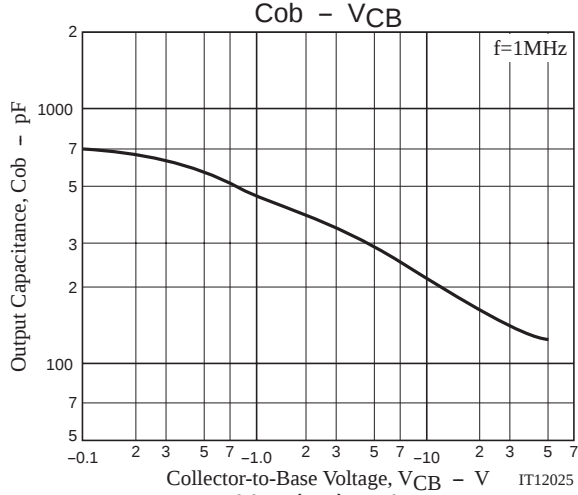
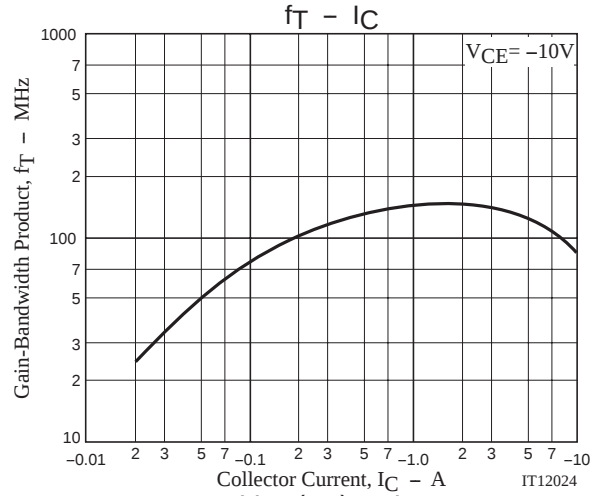
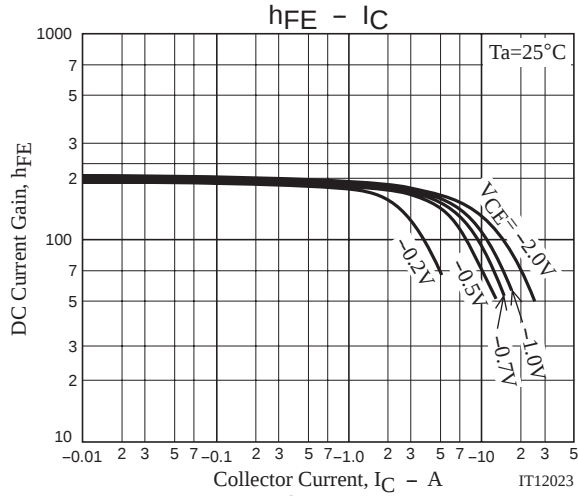
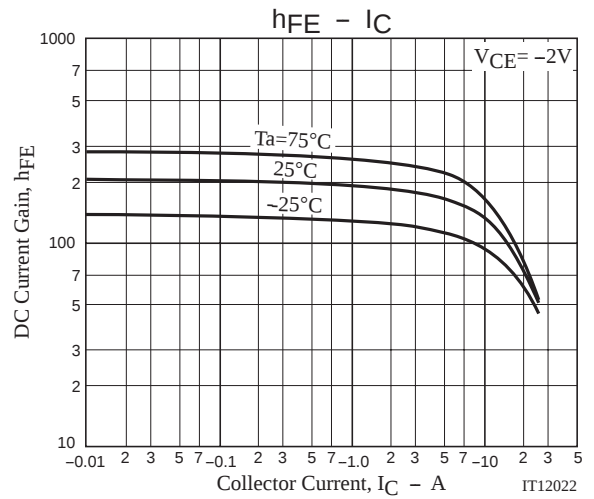
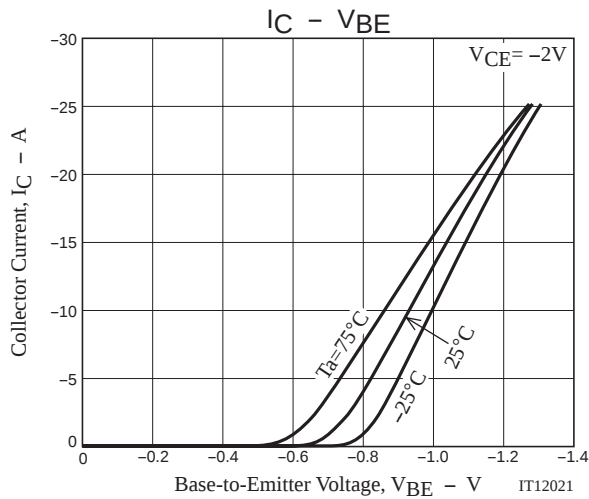
unit : mm (typ)

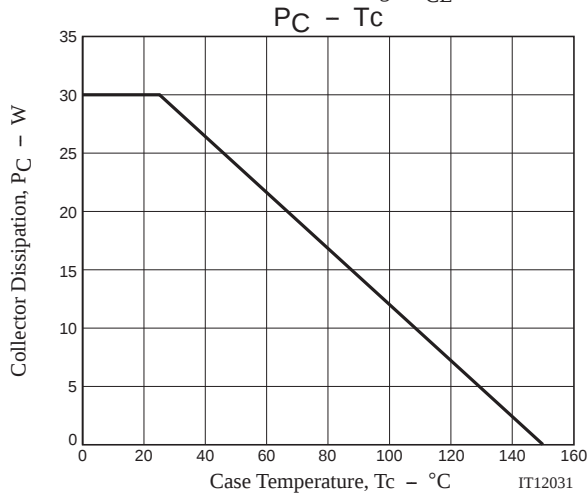
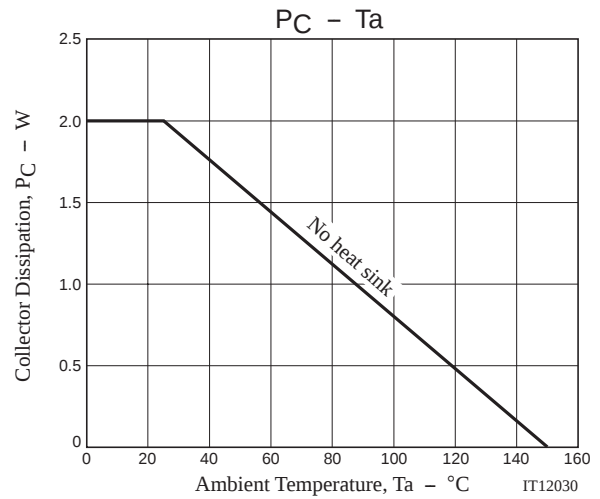
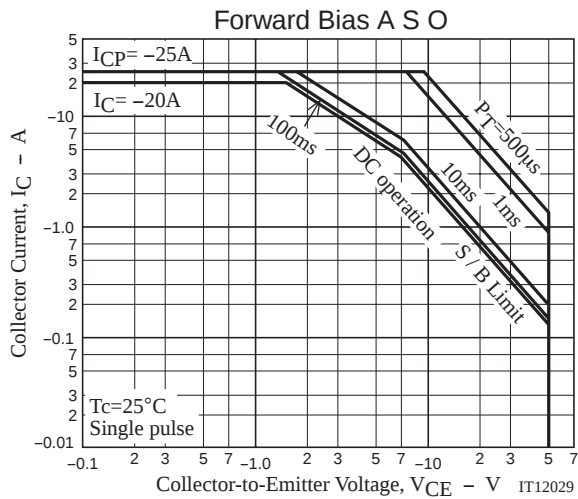
7508-002



Switching Time Test Circuit







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